## 類比電路佈局合成自動化 Automatic Layout Synthesis for Analog Circuits

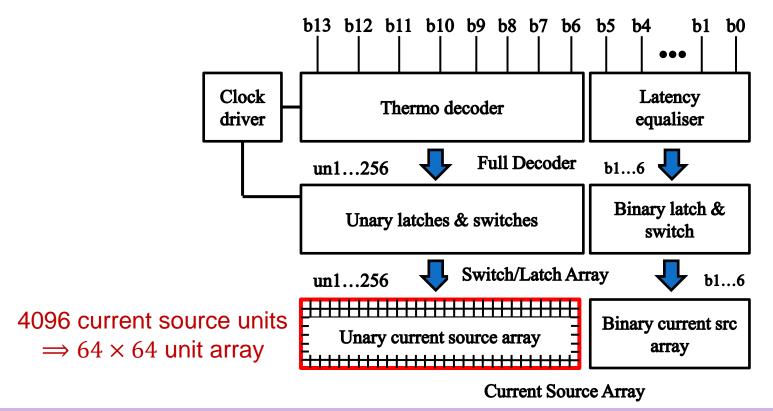
單元三同時考慮一階與二階系統製程變異的巨型矩陣元件擺置

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### Recall the DAC

- 14-bit current-steering digital-to-analog converter (DAC)
  - The 8 MSBs are decoded from a thermometer decoder that steers a unary-weighted current source array
  - The 6 LSBs steer the binary weighted current source array

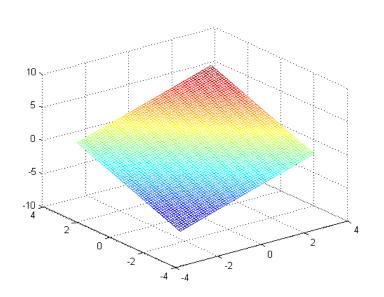




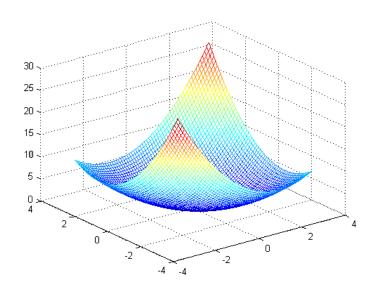
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## Systematic Mismatch Recap

- Caused by process variation, thermal distribution, uneven mechanical stress from other circuit layers, etc.
- Show up as spatial gradients in device parameters



First-order gradient



Second-order gradient

## **Gradient Error Computation**

 Thermal-induced or technology-rated gradient error can be approximated with a Taylor series expansion

$$p(x,y) = \sum_{i=1}^{\infty} G_i(x,y) + C$$

- (x, y): the location of a unit
- C: a constant independent of location
- $G_i(x,y)$ : the i-th order gradient error

$$G_i(x,y) = \sum_{j=0}^{i} g_{j,i-j} x^j y^{i-j}$$

- $\rightarrow g_{j,i-j}$ : the coefficient of  $x^j y^{i-j}$
- The lower order terms will have greater impacts on the mismatches among devices

## **Gradient Error Computation (cont'd)**

• The overall error by considering the first-order (linear) and the second-order (quadratic) gradients:

$$p(x,y) \approx G_1(x,y) + G_2(x,y)$$
  
=  $g_{1,0}x + g_{0,1}y + g_{2,0}x^2 + g_{1,1}xy + g_{0,2}y^2$ 

 Placements satisfying the common centroid constraint may have quite different 2<sup>nd</sup> order gradient errors

$a_1$	$b_1$	$c_1$	$d_1$
$a_2$	$b_2$	$c_2$	$d_2$
$d_3$	$c_3$	$b_3$	$a_3$
$d_4$	<i>c</i> <sub>4</sub>	$b_4$	$a_4$

1<sup>st</sup> order error: 0

Max 2<sup>nd</sup> order error: 20

$b_1$	$c_1$	$d_1$	$b_2$
$d_2$	$a_1$	$a_2$	$c_3$
$c_2$	$a_3$	$a_4$	$d_3$
$b_3$	$d_4$	$c_4$	$b_4$

1st order error: 0

Max 2<sup>nd</sup> order error: 18

$a_1$	$c_2$	$d_1$	$b_1$
$c_1$	$a_2$	$b_2$	$d_2$
$d_4$	$b_3$	$a_3$	$c_3$
$b_4$	$d_3$	C <sub>4</sub>	$a_4$

1st order error: 0

Max 2<sup>nd</sup> order error: 15

# **Integral Nonlinearity (INL)**

- The maximum difference between the ideal and the actual output levels for a DAC
  - The actual output level of the *u*-th unit of the *k*-th current source

$$p_{k,u}(x,y) = p_d + p(x,y)$$

- $\rightarrow p_d$ : the designed (default) output level
- The total output level of the kth current source

$$p_k = \sum_{u=1}^{num} p_{k,u}$$

The accumulated output level from the first current source to the *I*-th current source:

$$P(l) = \sum_{k=1}^{l} p_k$$

# Integral Nonlinearity (cont'd)

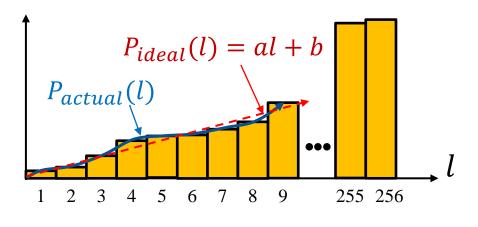
#### The ideal output level can be found by

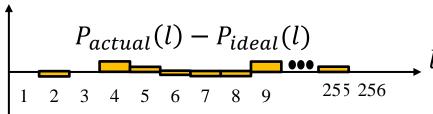
Find a best-fit line with a linear curve fitting method

$$P_{ideal}(l) = al + b$$

INL is the maximum difference between the ideal and the actual output levels

$$INL = \max_{l} |P_{actual}(l) - P_{ideal}(l)|$$







# **Simulated Annealing**

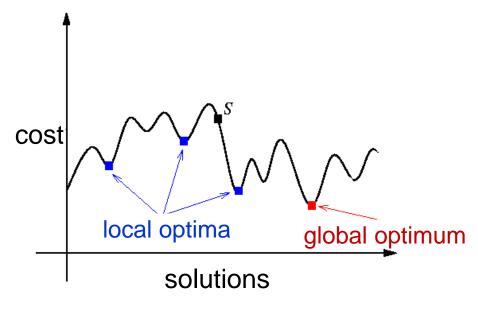


# Simulated Annealing (SA)

- Kirkpatrick, Gelatt, and Vecchi, "Optimization by simulated annealing," Science, May 1983.
- Simulated annealing is
  - Motivated by the physical annealing process
  - Used to solve optimization problems
  - A stochastic algorithm

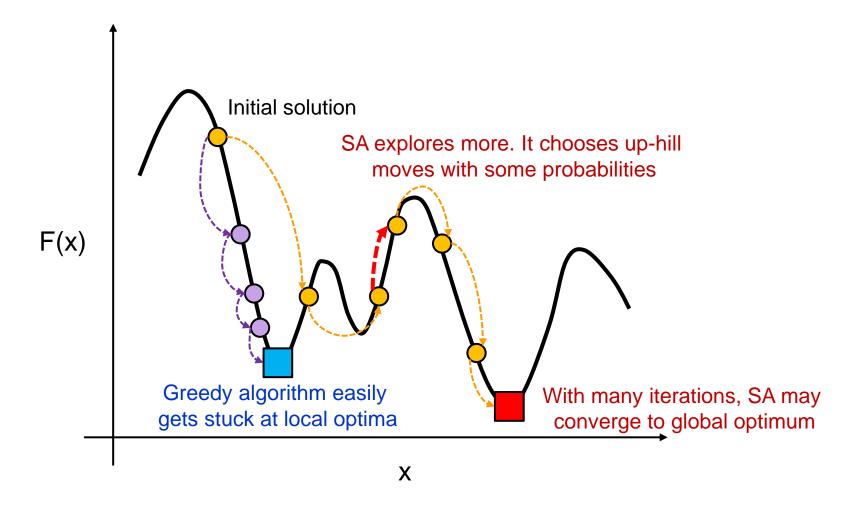
Escaping from local optima and finding the global optimum by allowing

worsening moves



## Simulated Annealing vs. Greedy Strategy

Use up-hill moves to escape from local optima

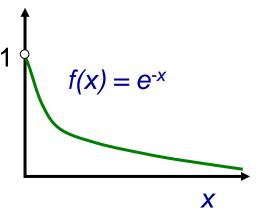


# Simulated Annealing Basics

- Given an initial/a current solution S with its cost cost(S)computed by an objective function
  - A neighboring solution S' is randomly picked
  - If S' has a lower cost, it is accepted
  - If S' has a higher cost, it still has a probability to be accepted

• 
$$Prob(S \rightarrow S') = \begin{cases} 1 & \text{, if } \Delta C \leq 0 \\ e^{-\frac{\Delta C}{T}} & \text{, if } \Delta C > 0 \end{cases}$$
 Down-hill moves  
•  $\Delta C = cost(S') - cost(S)$  Up-hill moves  
•  $T: \text{ control parameter (temperature)}$ 

- T: control parameter (temperature)
- Probability (T) depends on
  - Magnitude of the "up-hill" movement
  - Total search time



## **Generic Simulated Annealing Algorithm**

```
begin
2 Get an initial solution S;
   Get an initial temperature T > 0;
   while not yet "frozen" do
      for 1 < i < P do
         Pick a random neighbor S' of S;
         \Delta \leftarrow cost(S') - cost(S);
         /* downhill move */
         if \Delta \leq 0 then S \leftarrow S'
         /* uphill move */
         if \Delta > 0 then S \leftarrow S' with probability e^{-\overline{T}};
    T \leftarrow rT; /* reduce temperature */
11 return Best solution found
12 end
```



At a fixed

temperature

## **Basic Ingredients for Simulated Annealing**

#### Analogy:

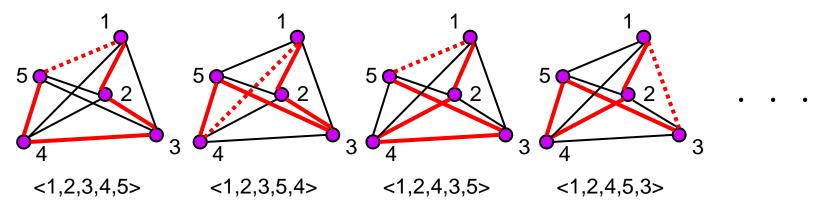
Physical system	Optimization problem
System state	Solution
Energy	Cost function
Ground state	optimal solution
Quenching	Local search
Real annealing	Simulated annealing

#### Basic Ingredients for Simulated Annealing:

- Solution space: What are the feasible solutions?
- Neighborhood structure: How to find a neighboring solution from the current one?
- Cost function: How to evaluate the quality of a solution?
- Annealing schedule: How to conduct the search process to find a desired solution? Starting temperature, stop criteria, cooling function?

## An Example: Traveling Salesman Problem

- The well-known traveling salesman problem (TSP)
  - Input: A set of points P (cities) together with a distance d(p, q) between any pair  $p, q \in P$
  - Output: The shortest circular route that starts and ends at a given point and visits all the points (cities)



4 of 5! solutions

Solve with simulated annealing?

## Simulated Annealing for TSP

#### Solution space

All permutations (n!) of the n points

#### Cost function

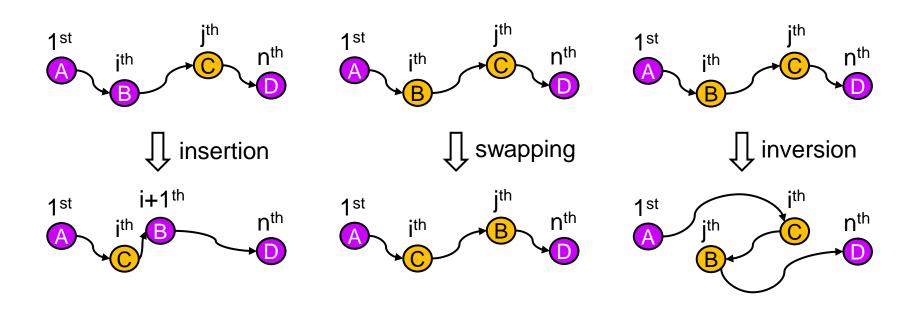
The total distance of the route represented by each permutation

#### Annealing schedule

- $T = < T_0, T_1, T_2, ... >$ , where  $T_i = r^i T_0, r < 1$
- At each temperature, try kn moves ( $k = 5 \sim 10$ ).
- Terminate the annealing process if, for example
  - # of accepted moves < 5%,</p>
  - Temperature is low enough, or
  - > Run out of time.

## Simulated Annealing for TSP (cont'd)

- Neighborhood structure: given a current route R, a neighbor R' may be generated by many operations:
  - Insert a point from position j to position i
  - Swap a pair of points at positions i and j
  - Invert the positions of the points between positions i and j



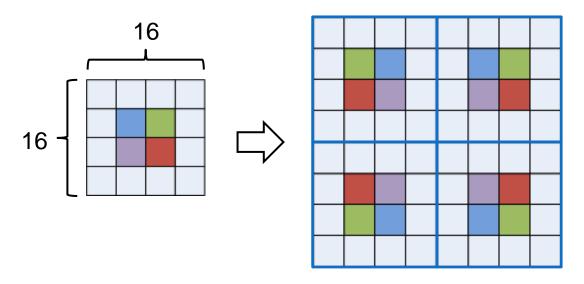


# Device Unit Array Placement for Quadratic Gradient Error Mitigation (LAB 3)



# **The Target Device Unit Array**

- An  $n \times n$  device unit array will be automatically placed
  - Each current source consists of 4 units (a simplified version)
  - Ex: 256 current sources will form a 32 × 32 current source unit array
- To follow the common centroid constraint
  - A quarter of the current source array is first determined  $\left(\frac{n}{2} \times \frac{n}{2}\right)$
  - The sub-array is then mirrored by the x- and y-axes



# **Device Array Placement**

- Fill the sub-array with the indices of the current sources
  - The current sources will be sequentially switched on according to the indices
  - Given the dimension  $\left(\frac{n}{2}\right)$  of the sub-array, the total number of current sources will be  $\left(\frac{n}{2}\right)^2$ , which are indexed in the range  $\left[0, \left(\frac{n}{2}\right)^2 1\right]$
- A placement of a sub-array with 16 current sources

0	1	2	3	
4	5	6	7	
8	တ	10	11	
12	13	14	15	

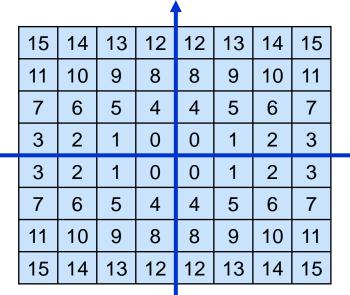
## **Objective**

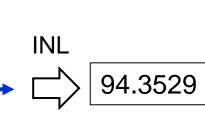
#### Derive a placement with the minimized INL

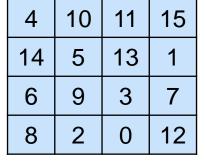
 The INL can be computed for the mirrored array of the original dimensions

0	1	2	3
4	5	6	7
8	တ	10	11
12	13	14	15











. . .



34.7765



## **SA-Based INL Minimization**

- Any operation swapping two sets (of the same size) of current source units may be conducted during SA
- Different swapping operations may be suitable for different stages in the annealing schedule

0	1	2	3		10	11	2	3
4	5	6	7	<b>/</b>	14	15	6	7
8	9	10	11	\/ '	8	9	0	1
12	13	14	15		12	13	4	5
0	1	2	3		0	1	2	3
4	5	6	7		4	14	6	7
8	9	10	11		8	9	10	11



# Lab 3: Device Array Placement

- Implement an SA-based current source unit array placement to minimize INL
  - Input: the dimension of the sub-array  $\frac{n}{2}$ , the default output level  $p_d$
  - Output: a unit sub-array (2D vector) with current source indices
  - Output format

$$\begin{bmatrix} I_{0,0} \end{bmatrix} \begin{bmatrix} I_{0,1} \end{bmatrix} \begin{bmatrix} I_{0,2} \end{bmatrix} \dots \begin{bmatrix} I_{0,\frac{n}{2}} \end{bmatrix}$$

$$\begin{bmatrix} I_{1,0} \end{bmatrix} \begin{bmatrix} I_{1,1} \end{bmatrix} \begin{bmatrix} I_{1,2} \end{bmatrix} \dots \begin{bmatrix} I_{1,\frac{n}{2}} \end{bmatrix}$$

$$\dots$$

$$\begin{bmatrix} I_{\frac{n}{2},0} \end{bmatrix} \begin{bmatrix} I_{\frac{n}{2},1} \end{bmatrix} \begin{bmatrix} I_{\frac{n}{2},2} \end{bmatrix} \dots \begin{bmatrix} I_{\frac{n}{2},\frac{n}{2}} \end{bmatrix}$$

#### Sample output file:

 $[I_{i,j}]$ : the index of the current source placed at (i,j) of the 2D vector

## Sample Code for Input and Output

 The provided code demonstrates command-line parameter, output file, and two placements with INL

```
int main(int argc, char **argv) {
    if(argc != 4) {
        cout << "Usage: ./[exe] [dimension of matrix] [p d]</pre>
                                                        [result.out]" << endl;</pre>
        exit(1);
    int dimension = atoi(argv[1]);
    int pd = atoi(argv[2]);
    Placer unit placer (dimension, pd);
    unit placer.demoBasicPlacement();
    unit placer.demoRandomPlacement();
    fstream fout;
    fout.open(argv[3], fstream::out);
    if(!fout.is open()){
        cout << "Error: the output file is not opened!!" << endl;</pre>
        exit(1);
    fout << "Hello world!" << endl;</pre>
    return 0:
```

## Sample Code for INL Computation

The computation of INL of a given sub-array has also been provided

```
double Placer::INL(vector< vector<int> > &matrix)
    vector<double> x;
    vector<double> v;
    vector<double> x2;
    vector<double> xy;
    const int n = dimension * _dimension;
    x.resize(n);
    v.resize(n);
    x2.resize(n);
    xy.resize(n);
    for (int i = 0; i < dimension; ++i)
        for (int j = 0; j < dimension; ++j)
            int deviceIdx = matrix[i][j];
            y[deviceIdx] = ((i + 0.5) * (i + 0.5) +
                                            (j + 0.5) * (j + 0.5) + pd) * 4;
```

## Sample Code for INL Computation (cont'd)

```
for (int i = 1; i < n; ++i) {
    v[i] += v[i - 1];
for(int i = 0; i < n; ++i){
    x[i] = i;
    x2[i] = i * i;
    xv[i] = i * v[i];
double sumX = accumulate(x.begin(), x.end(), 0.0);
double sumY = accumulate(v.begin(), y.end(), 0.0);
double sumX2 = accumulate(x2.begin(), x2.end(), 0.0);
double sumXY = accumulate(xv.begin(), xv.end(), 0.0);
// y = ax + b
double a = (n * sumXY - sumX * sumY) / (n * sumX2 - sumX * sumX);
double b = (sumY - a * sumX) / n;
vector<double> diff;
diff.resize(n);
for (int i = 0; i < n; ++i) {
    diff[i] = abs(v[i] - (a * i + b));
double inl = *max element(diff.begin(), diff.end());
return inl;
```